

## Silicon Carbide Enhancement Mode MOSFET

### Features

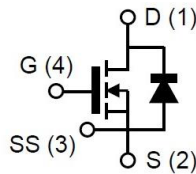
- High blocking voltage with low  $R_{DS(on)}$
- High frequency operation with low Capacitance
- Simple to drive with -4V/+15V gate
- Robust body diode with low  $Q_{rr}$
- 100% Avalanche Tested

### Benefits

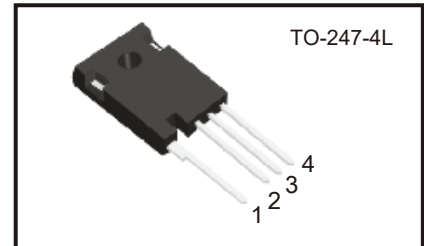
- Superior robustness and system reliability
- Higher system efficiency
- Easier paralleling without thermal runaway
- Capable of high temperature application
- Faster and more efficient switching

### Applications

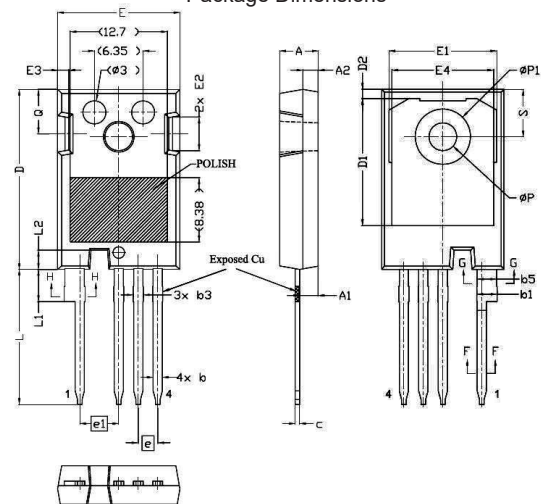
- EV motor drives
- EV/HEV charging station
- Energy storage and Battery charging
- High voltage DC-DC converters
- Solar / Wind Inverters
- UPS and PFC



$V_{DSS}$	750V
$I_D(@25^{\circ}C)$	80A
$R_{DS(ON) typ.}$	30mΩ



Package Dimensions



### Absolute Maximum Ratings

( $T_c = 25^{\circ}C$  unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage $V_{GS}=0V$ $I_D=100\mu A$	$V_{DS}$	750	V
Gate-Source Voltage (dynamic) AC ( $f>1$ Hz, duty cycle<1%, pulse width<200ns)	$V_{GS}$	-10/+23	V
Gate-Source Voltage (static)	$V_{GS(op)}$	-4/+15	V
Drain Current-Continuous $V_{GS}=20V@ T_c=25^{\circ}C$ $V_{GS}=20V@ T_c=100^{\circ}C$	$I_D$	80 60	A
Pulse Drain Current	$I_{D,pulse}$	166	A
Power Dissipation	$P_D$	320	W
Storage Temperature Range	$T_{STG}$	-55 to +175	$^{\circ}C$
Operating Junction Temperature Range	$T_J$	-55 to +175	$^{\circ}C$
Soldering Temperature	$T_L$	260	$^{\circ}C$
Avalanche Capability, single pulse * $V_{DD}=100V$ $V_{GS}=10V$ $L=2mH$	$I_{AV}$	40	A
Avalanche Capability, single pulse** $V_{DD}=100V$ $V_{GS}=10V$ $L=2mH$	$E_{AV}$	1600	mJ
Short Circuit Capability $V_{DD}=500V, V_{GS}=15V$	$t_{sc}$	4	$\mu S$

\* 100% tested in 50% rating

\*\* 100% tested in 25% rating

SYMBOL	DIMENSIONS			SYMBOL	DIMENSIONS		
	MIN.	NOM.	MAX.		MIN.	NOM.	MAX.
A	4.83	5.02	5.21	E	15.75	15.94	16.13
A1	2.29	2.41	2.54	E1	13.10	14.02	14.15
A2	1.91	2.00	2.16	E2	3.68	4.40	5.10
b'	1.07	1.20	1.28	E3	1.00	1.45	1.90
b	1.07	1.20	1.33	E4	12.38	13.26	13.43
b1	2.39	2.67	2.94	e	2.54 BSC		
b2	2.39	2.67	2.84	e1	5.08 BSC		
b3	1.07	1.30	1.60	L	17.31	17.57	17.82
b4	1.07	1.30	1.50	L1	3.97	4.19	4.37
b5	2.39	2.53	2.69	L2	2.35	2.50	2.65
b6	2.39	2.53	2.64	ØP	3.51	3.61	3.65
c	0.55	0.60	0.68	ØP1	7.19 REF.		
c1	0.55	0.60	0.65	Q	5.49	5.79	6.00
D	23.30	23.45	23.60	S	6.04	6.17	6.30
D1	16.25	16.55	17.65				
D2	0.95	1.19	1.25				

**Electrical Characteristics @  $T_c = 25^\circ\text{C}$  (unless otherwise specified)**

Parameter	Symbol	Conditions		Min.	Typ.	Max.	Unit
OFF Characteristics							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V , I <sub>D</sub> =0.1mA		750	-	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =750V V <sub>GS</sub> =0V	T <sub>J</sub> =25℃	-	0.5	60	μA
			T <sub>J</sub> =175℃	-	5	200	
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =15V , V <sub>DS</sub> =0V		-	5	100	nA
		V <sub>GS</sub> =-4V , V <sub>DS</sub> =0V		-100	-5	-	
ON Characteristics							
Gate Threshold Voltage ***	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> =20mA	T <sub>J</sub> =25℃	1.8	2.4	3.2	V
			T <sub>J</sub> =175℃	-	1.65	-	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =15V , I <sub>D</sub> =30A	T <sub>J</sub> =25℃	-	26	40	mΩ
			T <sub>J</sub> =175℃	-	39	-	
Transconductance	g <sub>fs</sub>	V <sub>DS</sub> =20V , I <sub>D</sub> =30A	T <sub>J</sub> =25℃	-	24	-	S
			T <sub>J</sub> =175℃	-	23	-	
Internal Gate Resistance	R <sub>G(int.)</sub>	f =1MHz , I <sub>D</sub> =0A		-	3.0	-	Ω
Dynamic Characteristics							
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =500V V <sub>GS</sub> =0V f =1MHz V <sub>AC</sub> =25mV	-	2800	-	pF	
Output Capacitance	C <sub>oss</sub>		-	180	-		
Reverse Transfer Capacitance	C <sub>rss</sub>		-	5	-		
Coss Stored Energy	E <sub>oss</sub>		-	27	-	μJ	
Turn-On Switching Energy	E <sub>on</sub>	V <sub>DS</sub> =500V , V <sub>GS</sub> =-4/+15V I <sub>D</sub> =40A , R <sub>G(ext)</sub> =2.0Ω L =200μH	-	105	-	μJ	
Turn-Off Switching Energy	E <sub>off</sub>		-	75	-		
Switching Characteristics							
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> =500V , V <sub>GS</sub> =-4/+15V I <sub>D</sub> =40A , R <sub>G(ext)</sub> =2.0Ω L =200μH	-	15	-	ns	
Rise Time	t <sub>r</sub>		-	19	-		
Turn-Off Delay Time	t <sub>d(off)</sub>		-	35	-		
Fall Time	t <sub>f</sub>		-	8	-		
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> =500V V <sub>GS</sub> =-4/+15V I <sub>D</sub> =40A	-	125	-	nC	
Gate to Source Charge	Q <sub>gs</sub>		-	35	-		
Gate to Drain Charge	Q <sub>gd</sub>		-	35	-		
Body Diode Characteristics							
Inverse Diode Forward Voltage	V <sub>SD</sub>	V <sub>GS</sub> =-4V , I <sub>SD</sub> =20A	T <sub>J</sub> =25℃	-	4	-	V
Inverse Diode Forward Voltage			T <sub>J</sub> =175℃	-	3.5	-	V
Continuous Diode Forward Current	I <sub>S</sub>	V <sub>GS</sub> =-4V , T <sub>J</sub> =25℃		-	60	-	A
Reverse Recovery Time	T <sub>rr</sub>	I <sub>SD</sub> =40A , V <sub>GS</sub> =-4V		-	25	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>	V <sub>R</sub> =500V , T <sub>J</sub> =25℃		-	330	-	nC
Peak Reverse Recovery Current	I <sub>rrm</sub>	dif/dt=2400A/μs		-	25	-	A
Thermal Resistance							
Thermal Resistance, Junction-to-Case	Rθ <sub>Jc</sub>			-	0.45	0.47	℃/W

\*\*\* Turn-off with -4V gate bias is highly recommended

## Typical Performance

Fig 1. Output Characteristics,  $T_J = -40^\circ\text{C}$

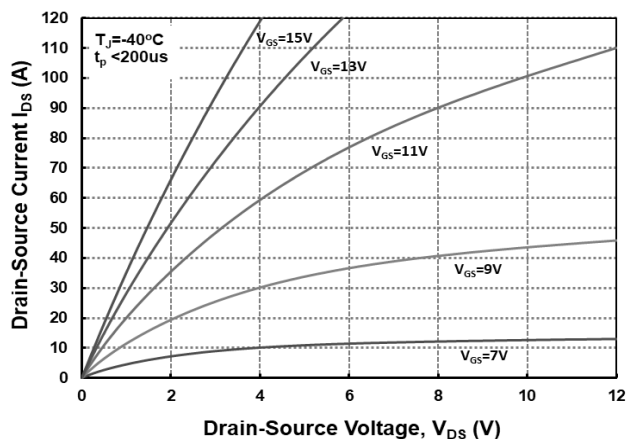


Fig 2. Output Characteristics,  $T_J = 25^\circ\text{C}$

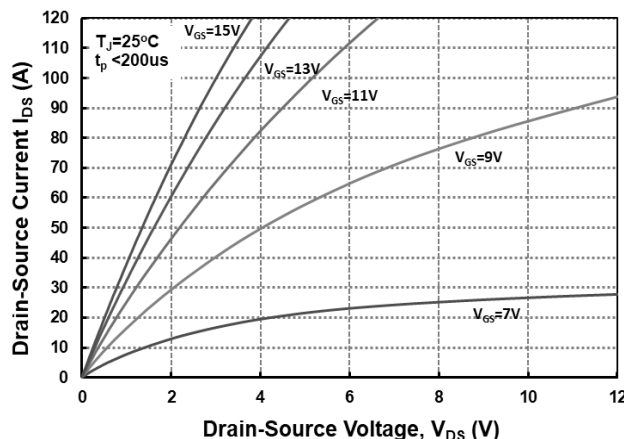


Fig 3. Output Characteristics,  $T_J = 175^\circ\text{C}$

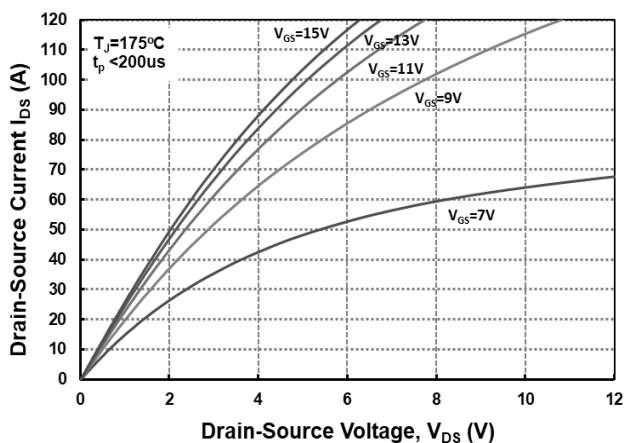


Fig 4. Normalized On-Resistance vs. Temperature

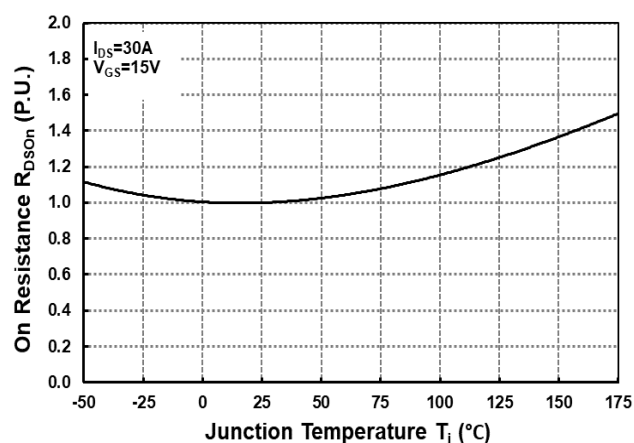


Fig 5. On-Resistance vs. Drain Current for Various Temperatures

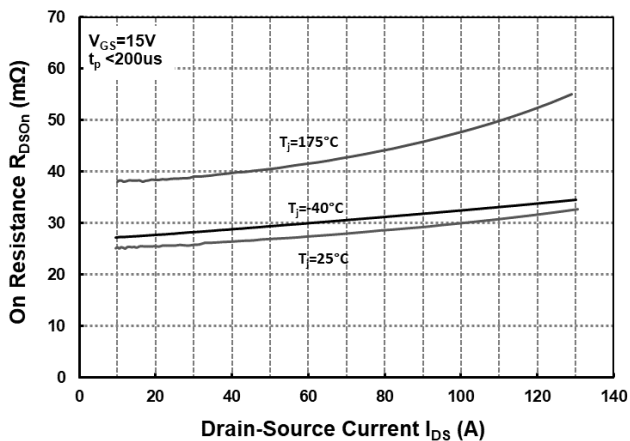
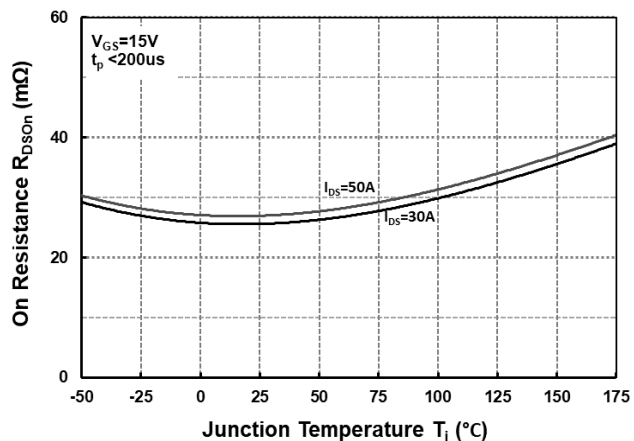
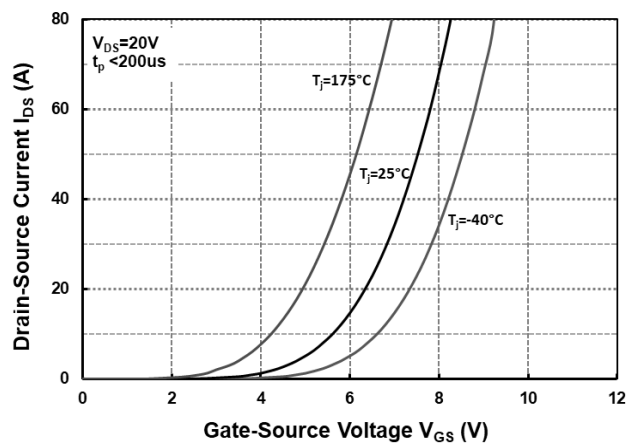


Fig 6. On-Resistance vs. Temperature for Various Drain-Source Current

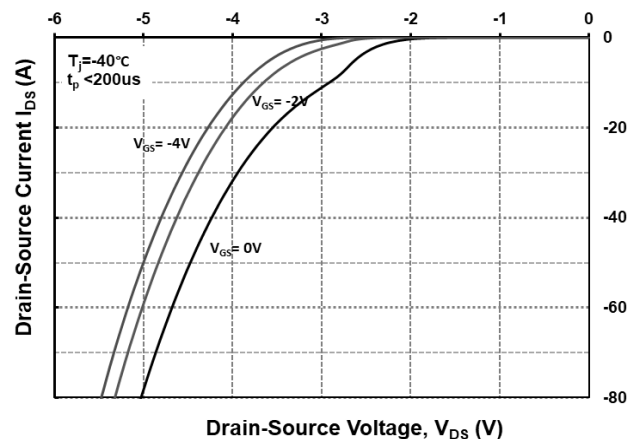


## Typical Performance

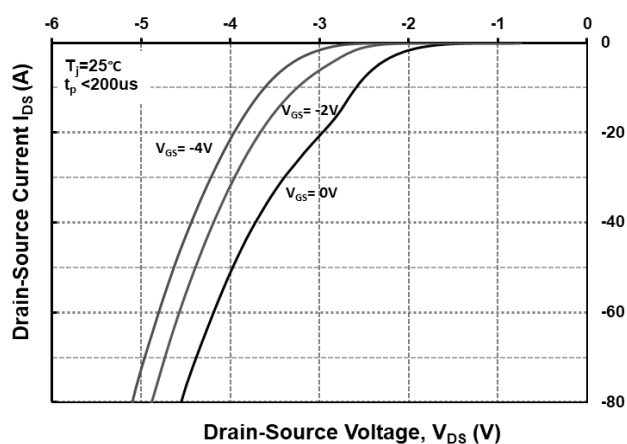
**Fig 7. Transfer Characteristic for Various Junction Temperatures**



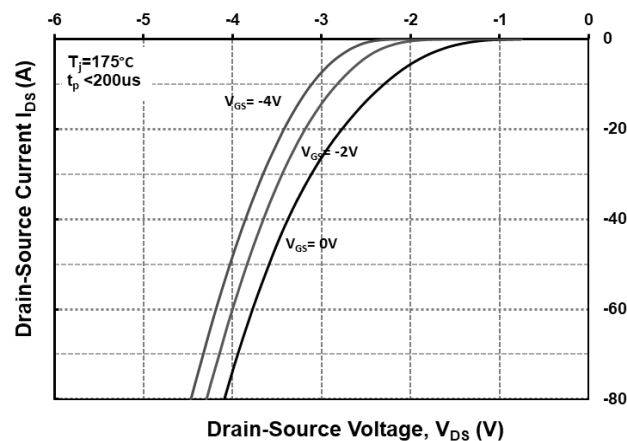
**Fig 8. Body Diode Characteristics @  $-40^\circ C$**



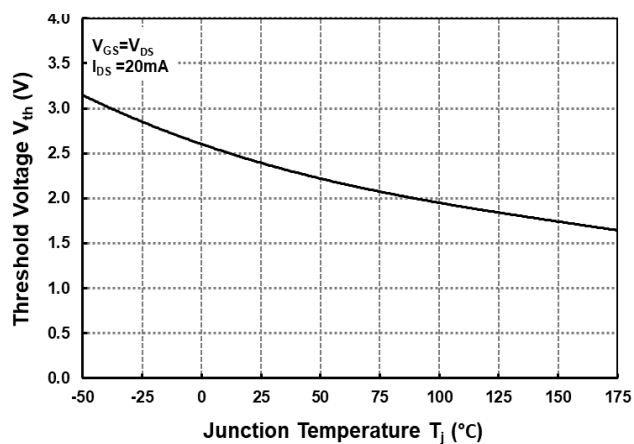
**Fig 9. Body Diode Characteristics @  $25^\circ C$**



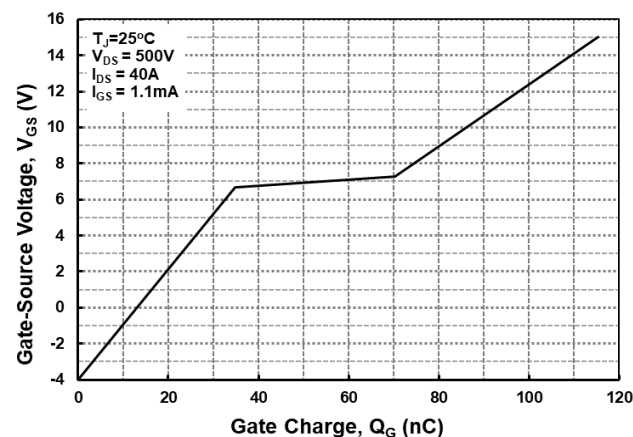
**Fig 10. Body Diode Characteristics @  $175^\circ C$**



**Fig 11. Threshold Voltage vs. Temperature**



**Fig 12. Gate Charge Characteristics**



## Typical Performance

Fig 13. 3<sup>rd</sup> Quadrant Characteristics @ -40°C

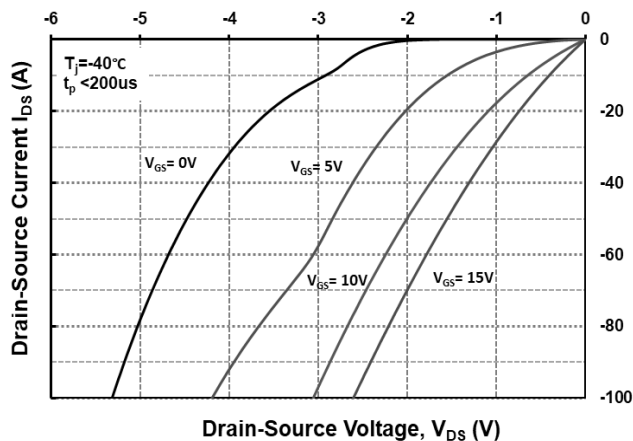


Fig 14. 3<sup>rd</sup> Quadrant Characteristics @ 25°C

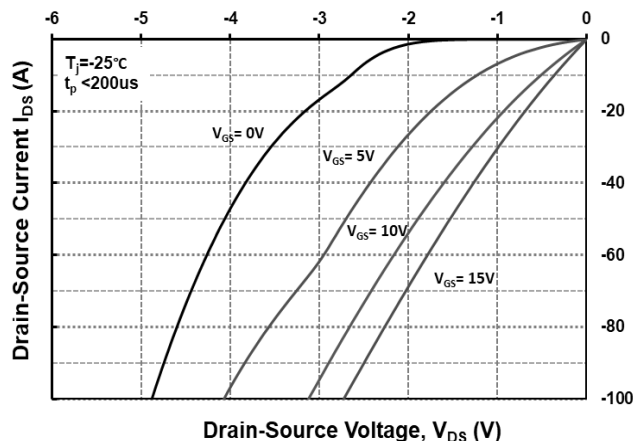


Fig 15. 3<sup>rd</sup> Quadrant Characteristics @ 175°C

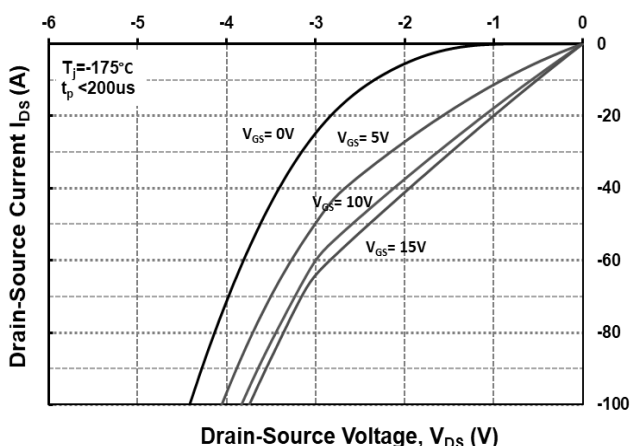


Fig 16. Output Capacitor Stored Energy

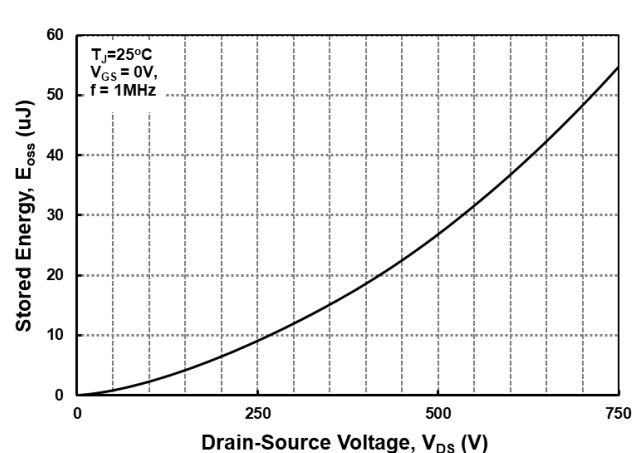


Fig 17. Capacitances vs. Drain-Source Voltage (0-200V)

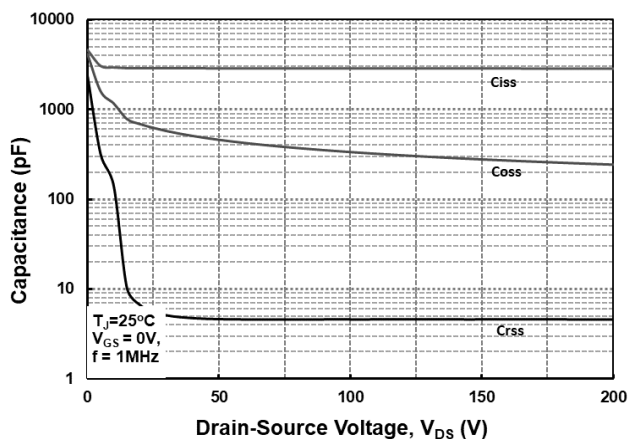
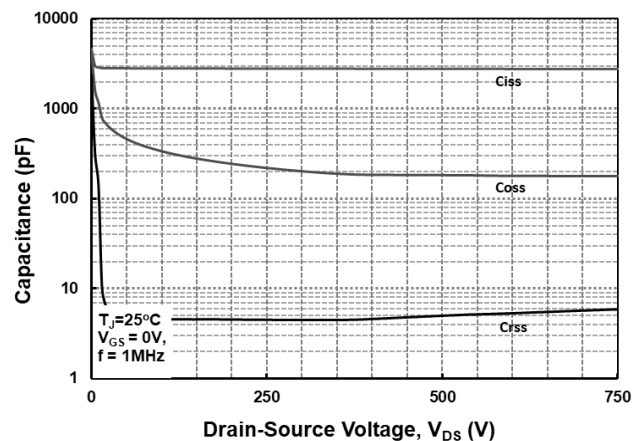


Fig 18. Capacitances vs. Drain-Source Voltage (0-750V)





## Typical Performance

Fig 19. Continuous Drain Current Derating

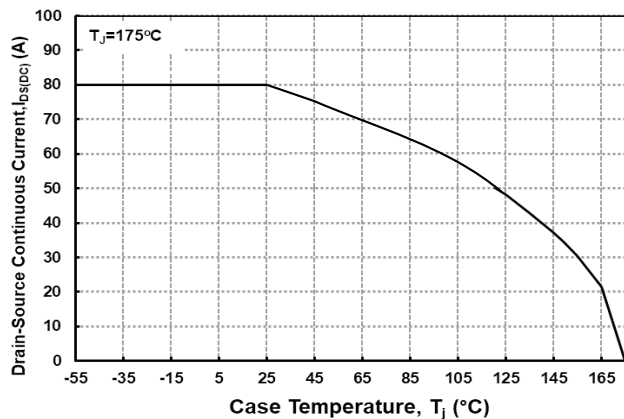


Fig 20. Maximum Power Dissipation Derating vs. Case Temperature

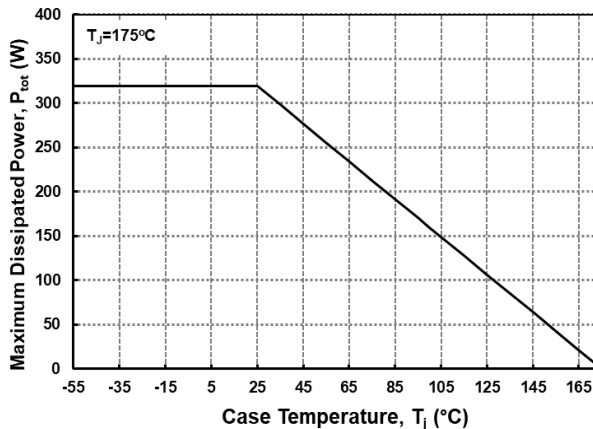


Fig 21. Transient Thermal Impedance (Junction-Case)

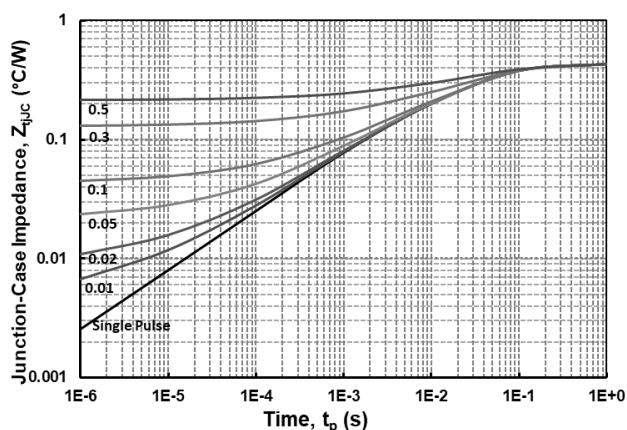


Fig 22. Safe Operating Area

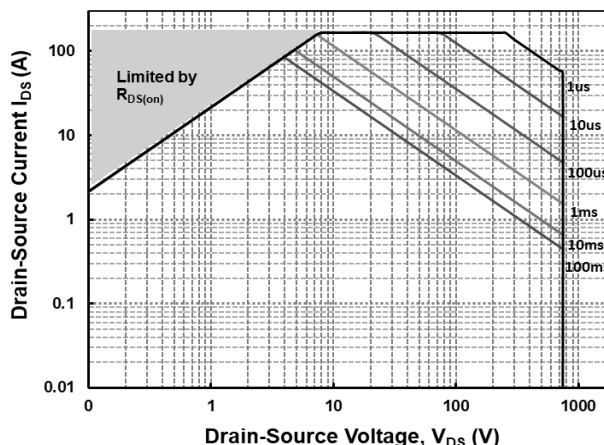


Fig 23. Clamped Inductive Switching Energy vs Drain Current ( $V_{DD} = 500V$ )

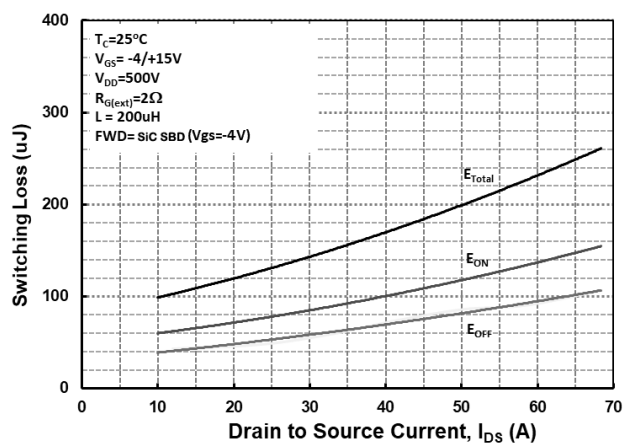
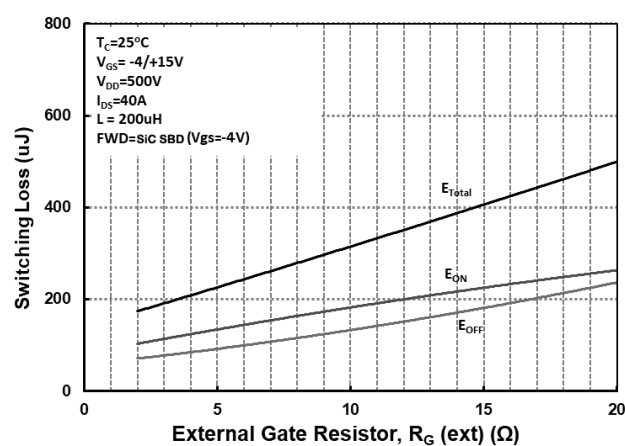
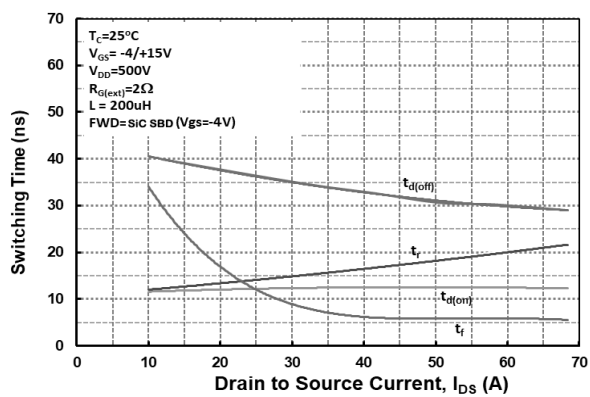


Fig 24. Clamped Inductive Switching Energy vs External Gate Resistor  $R_{G(ext)}$

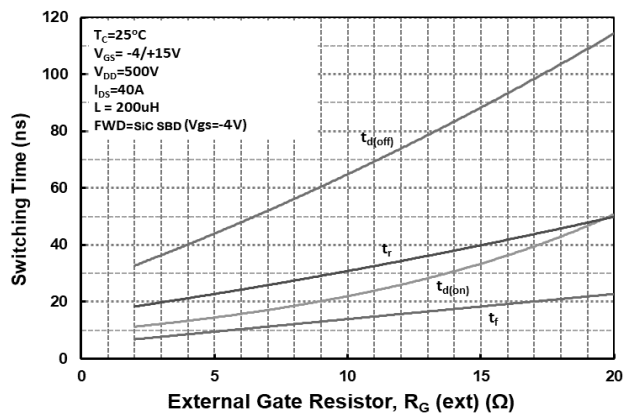


## Typical Performance

**Fig 25. Switching Times vs Drain Current**  
( $V_{DD} = 500V$ )



**Fig 26. Switching Times vs External Gate Resistor  $R_{G(ext)}$**



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